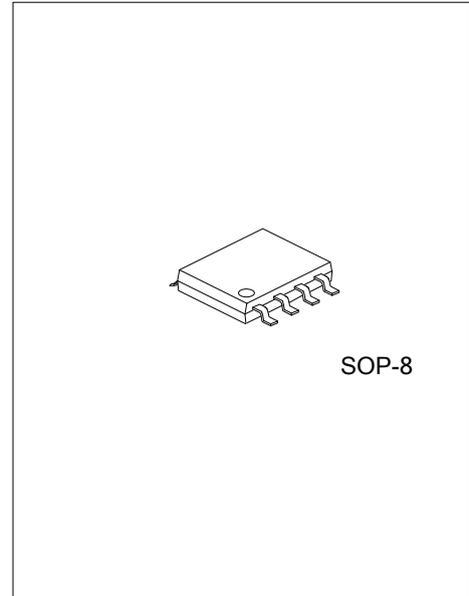




UTT15NN06

Power MOSFET

**15A, 60V DUAL N-CHANNEL
ENHANCEMENT MODE
POWER MOSFET**



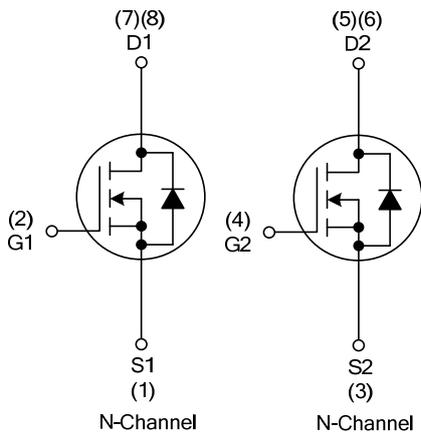
■ DESCRIPTION

The UTC **UTT15NN06** is a N-channel Power MOSFET, it uses UTC's advanced technology to provide the customers with low R_{DS(ON)} characteristic by high cell density trench technology.

■ FEATURES

- * R_{DS(ON)} ≤ 35 mΩ @ V_{GS}=10V, I_D=7.5A
- R_{DS(ON)} ≤ 53 mΩ @ V_{GS}=4.5V, I_D=7.5A
- * Fast Switching Speed
- * Simple Drive Requirement

■ SYMBOL



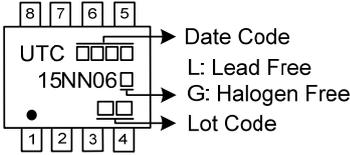
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment						Packing		
Lead Free	Halogen Free		1	2	3	4	5	6		7	8
UTT15NN06L-S015-R	UTT15NN06G-S015-R	SOP-15	S1	G1	S2	G2	D2	D2	D1	D1	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>UTT15NN06G-S08-R</p> <p>(1)Packing Type (2)Package Type (3)Green Package</p>	<p>(1) R: Tape Reel (2) S08: SOP-8 (3) G: Halogen Free and Lead Free, L: Lead Free</p>
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■ MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_A=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Drain-Source Voltage	V_{DSS}	60	V
Gate-Source Voltage	V_{GSS}	± 20	V
Drain Current	Continuous	I_D	15
	Pulsed (Note 2)	I_{DM}	30
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	14.1
Peak Diode Recovery dv/dt (Note 4)	dv/dt	1.7	V/nS
Power Dissipation	P_D	2	W
Junction Temperature	T_J	+150	$^{\circ}\text{C}$
Storage Temperature	T_{STG}	-55 ~ +150	$^{\circ}\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L = 0.1\text{mH}$, $I_{AS} = 16.8\text{A}$, $V_{DD} = 25\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^{\circ}\text{C}$.

4. $I_{SD} \leq 15\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(BR)DSS}$, $T_J = 25^{\circ}\text{C}$.

■ THERMAL DATA (NOTE)

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	125	$^{\circ}\text{C}/\text{W}$
Junction to Case	θ_{JC}	62.5	$^{\circ}\text{C}/\text{W}$

Note: Device mounted on FR-4 substrate P_c board, 2oz copper, with 1inch square copper plate.

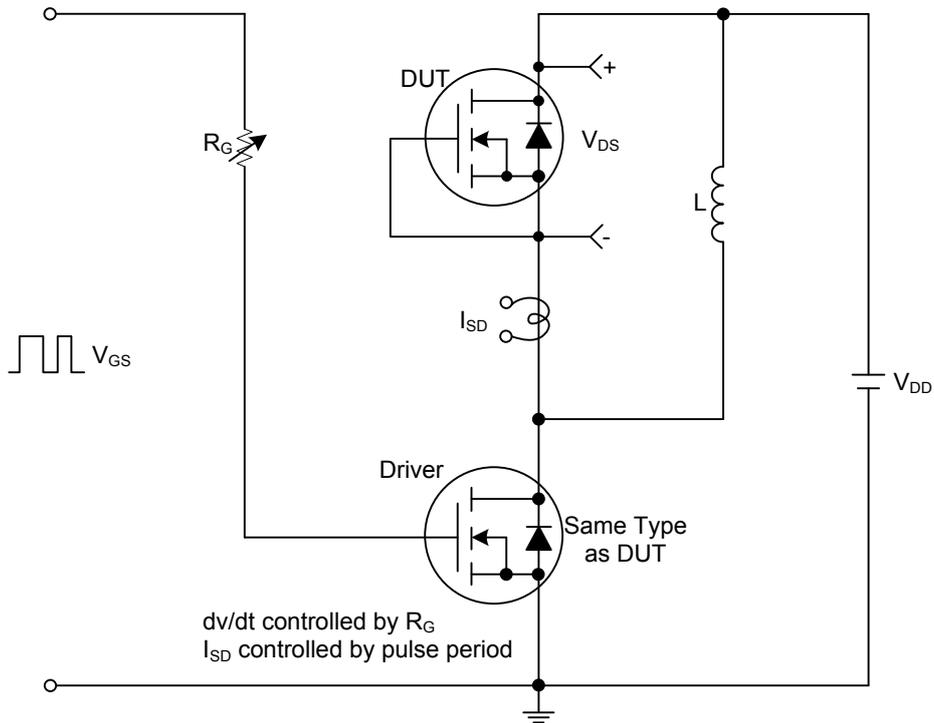
■ ELECTRICAL CHARACTERISTICS (T_J=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	60			V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =60V, V _{GS} =0V			1	μA
Gate-Source Leakage Current	Forward	V _{DS} =0V, V _{GS} =20V			60	nA
	Reverse		V _{DS} =0V, V _{GS} =-20V			-60
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	1.0		3.0	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =7.5A			35	mΩ
		V _{GS} =4.5V, I _D =7.5A			53	mΩ
DYNAMIC PARAMETERS						
Input Capacitance	C _{ISS}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz		817.1		pF
Output Capacitance	C _{OSS}			85.7		pF
Reverse Transfer Capacitance	C _{RSS}			74.7		pF
SWITCHING PARAMETERS						
Total Gate Charge (Note 1)	Q _G	V _{DS} =48V, V _{GS} =10V, I _D =15A, I _G =1mA (Note 1, 2)		28.8		nC
Gate-Source Charge	Q _{GS}			5.8		nC
Gate-Drain Charge	Q _{GD}			8		nC
Turn-ON Delay Time (Note 1)	t _{D(ON)}	V _{DD} =30V, V _{GS} =10V, I _D =15A, R _G =3Ω (Note 1, 2)		8		ns
Turn-ON Rise Time	t _R			15.5		ns
Turn-OFF Delay Time	t _{D(OFF)}			18.4		ns
Turn-OFF Fall Time	t _F			18.6		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Body-Diode Continuous Current	I _S				15	A
Maximum Body-Diode Pulsed Current	I _{SM}				30	A
Drain-Source Diode Forward Voltage (Note 1)	V _{SD}	I _S =15A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time (Note 1)	t _{rr}	I _S =15A, V _{GS} =0V, dI _F /dt=100A/μs		22		ns
Body Diode Reverse Recovery Charge	Q _{rr}				31	

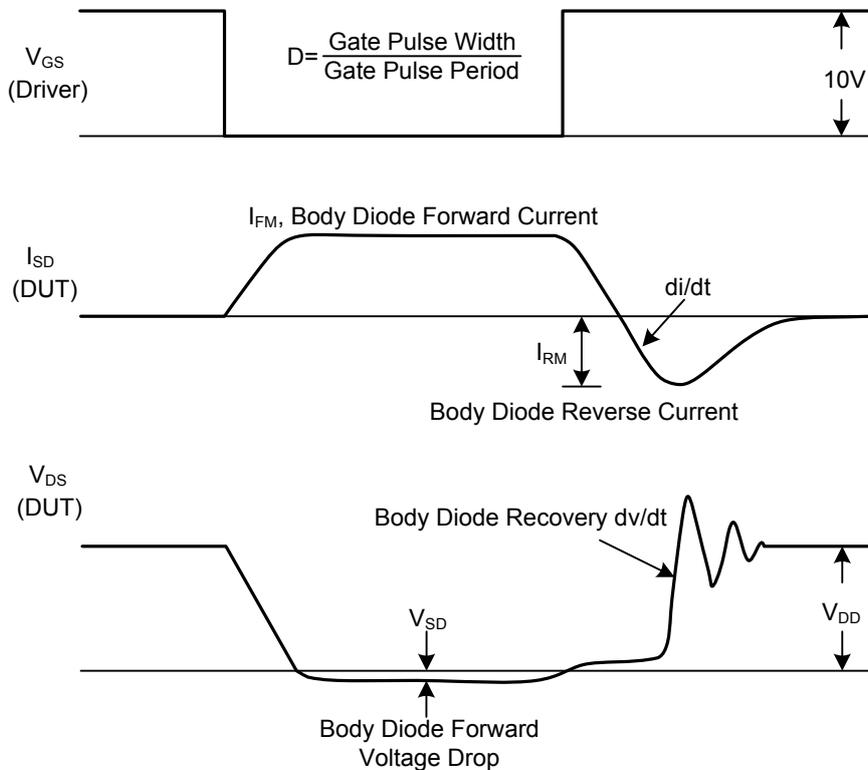
Notes: 1. Pulse Test: Pulse width ≤ 600μs, Duty cycle ≤ 2%.

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS



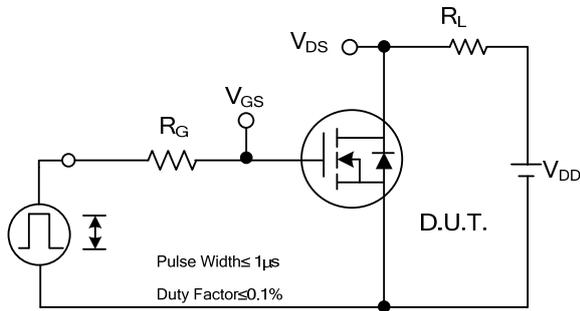
Peak Diode Recovery dv/dt Test Circuit



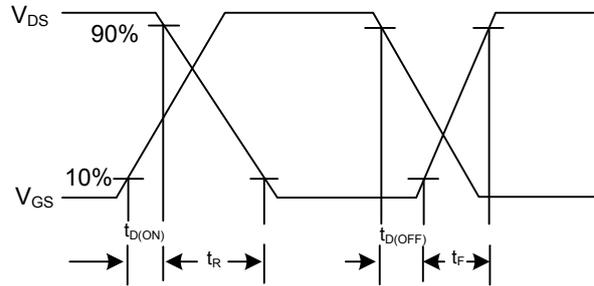
Peak Diode Recovery dv/dt Test Circuit and Waveforms

Peak Diode Recovery dv/dt Waveforms

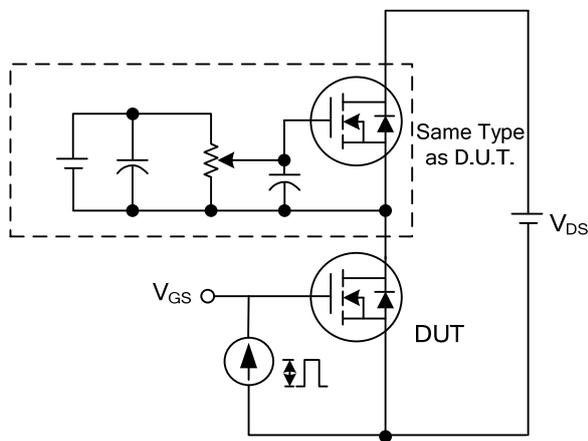
TEST CIRCUITS AND WAVEFORMS



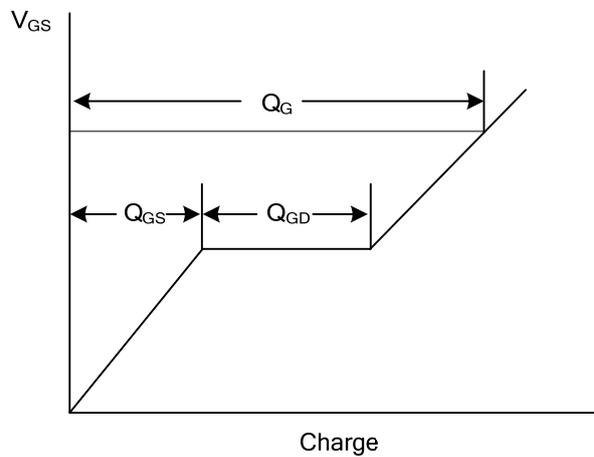
Switching Test Circuit



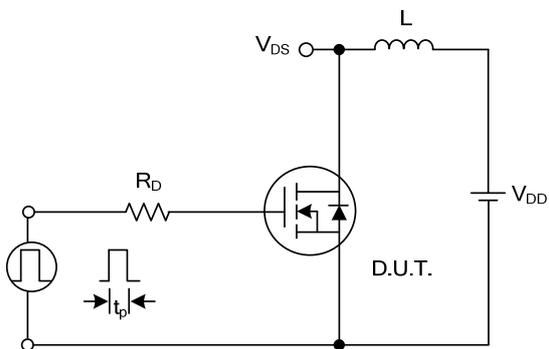
Switching Waveforms



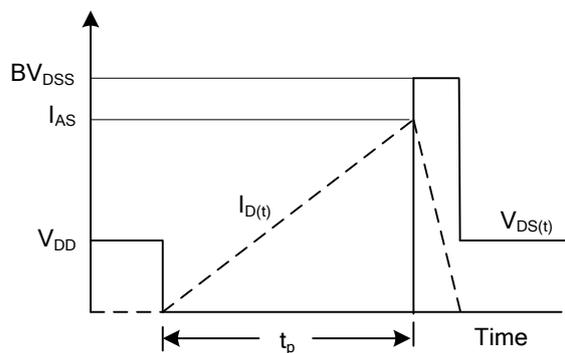
Gate Charge Test Circuit



Gate Charge Waveform

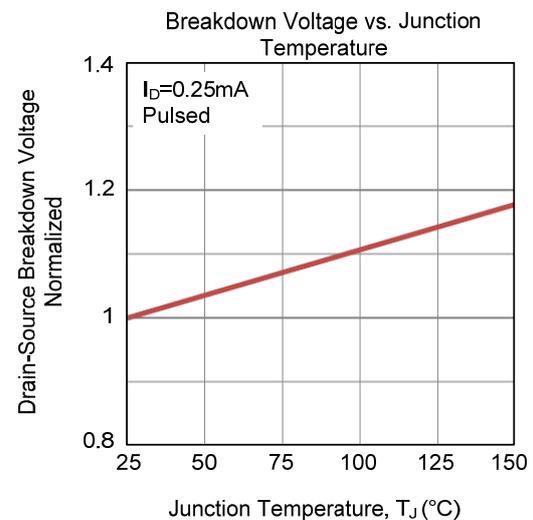
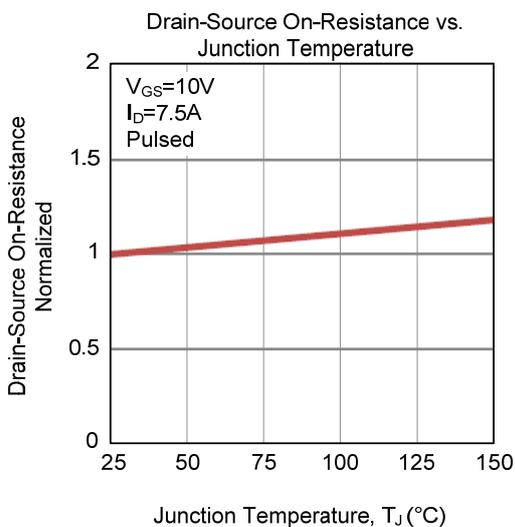
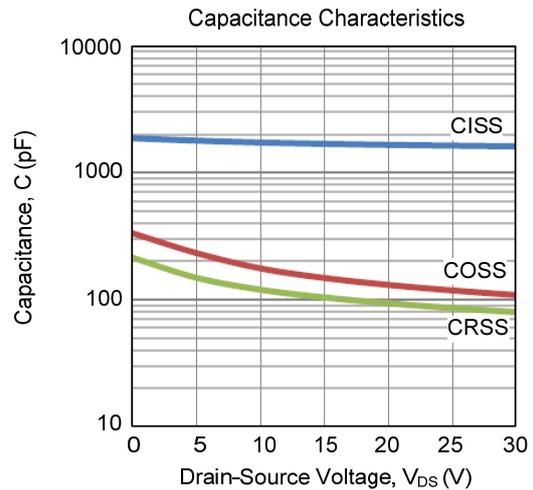
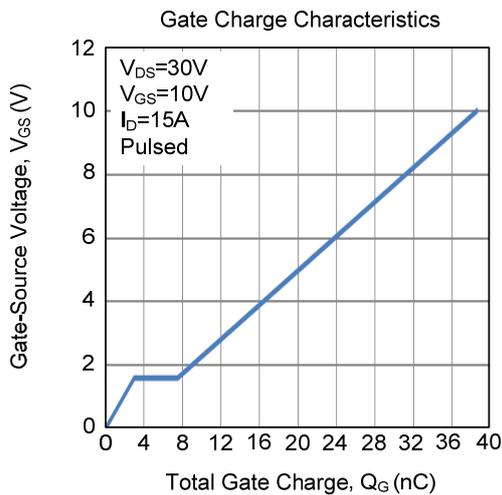
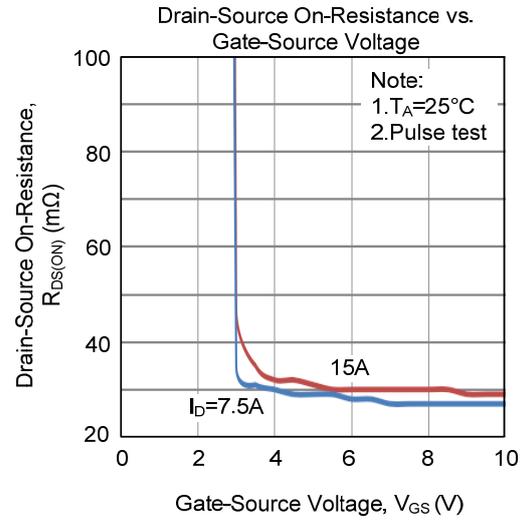
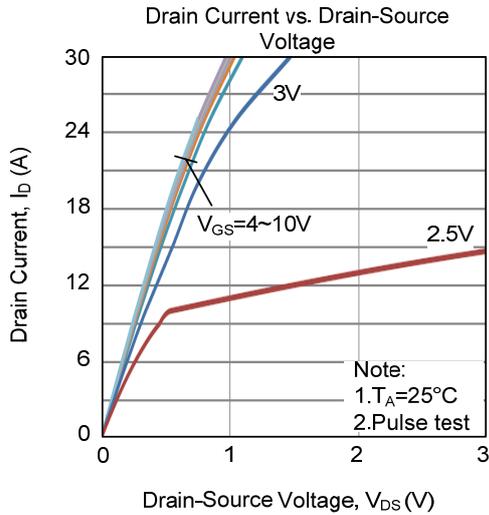


Unclamped Inductive Switching Test Circuit

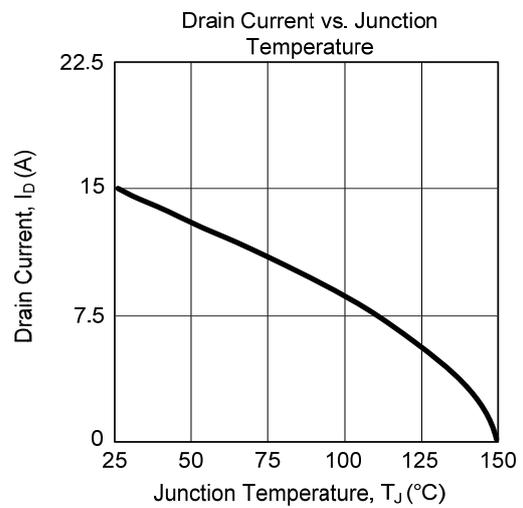
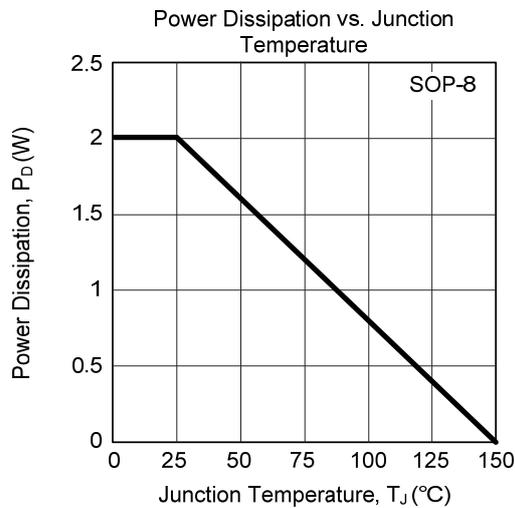
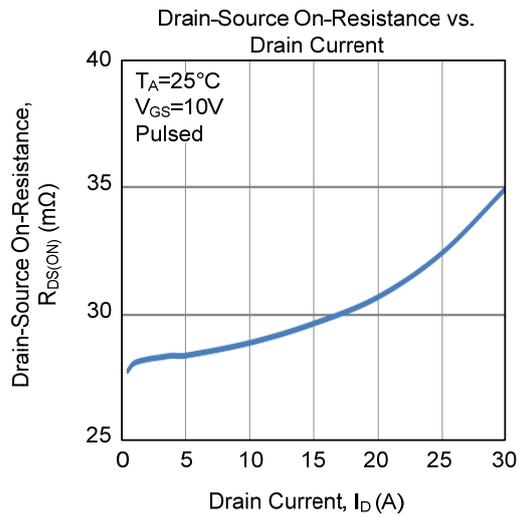
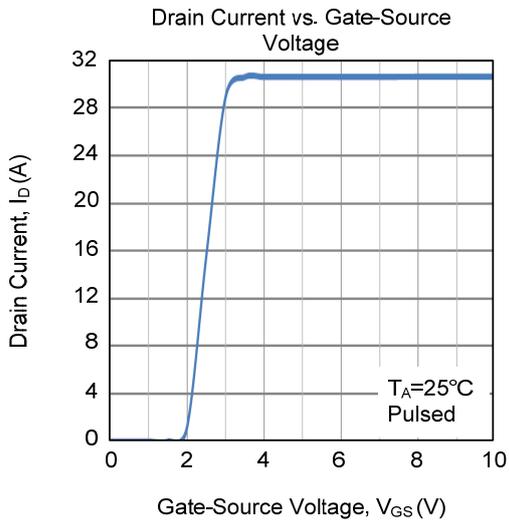
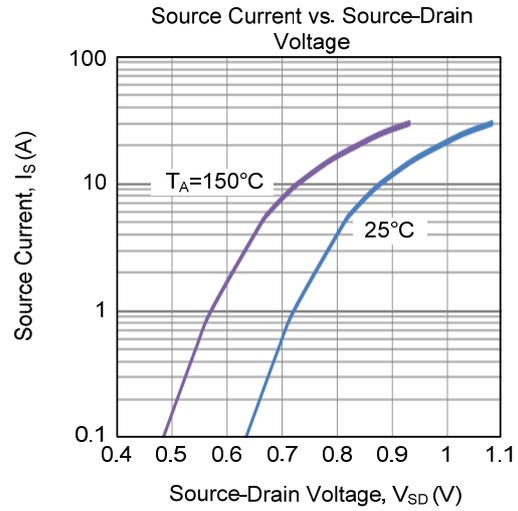
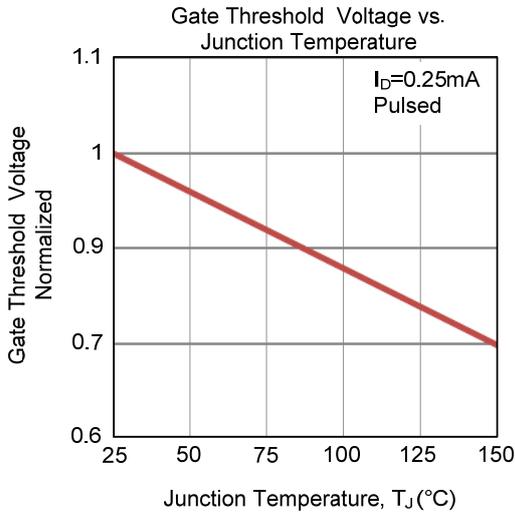


Unclamped Inductive Switching Waveforms

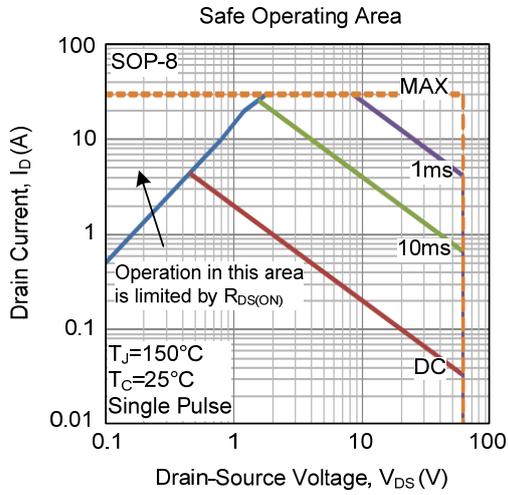
TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS (Cont.)



■ TYPICAL CHARACTERISTICS (Cont.)



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